IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application)	PATENT APPLICATION
Inventors:		Ware, et al.)	Art Unit: 2829
Application No.:		10/768,443)	
Filed Date:		January 30, 2004)	Examiner: Nguyen, Trung Q.
Title:	METHOD AND APPARATUS FOR TEST AND CHARACTERIZATION OF SEMICONDUCTOR COMPONENTS))))	Customer No.: 38456

AMENDMENT UNDER 37 C.F.R. § 1.312(a)

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

This AMENDMENT is made after the Notice of Allowance under 37 C.F.R. § 1.312.

AMENDMENTS to the CLAIMS begin on Page 2 of this paper.

REMARKS begin on Page 5 of this paper.